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United States Patent [19]

Kaneko et al.

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[45] **Date of Patent: ** Jun. 27, 2000**

[54] **MEASUREMENT SURVEYING DEVICE**

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[**] Term: **14 Years**

[21] Appl. No.: **29/106,606**

[22] Filed: **Jun. 21, 1999**

[30] **Foreign Application Priority Data**

Mar. 19, 1999 [JP] Japan .... D 11-7141

[51] **LOC (7) Cl.** **10-04**

[52] **U.S. Cl.** **D10/66**

[58] **Field of Search** D10/66; 33/290–299

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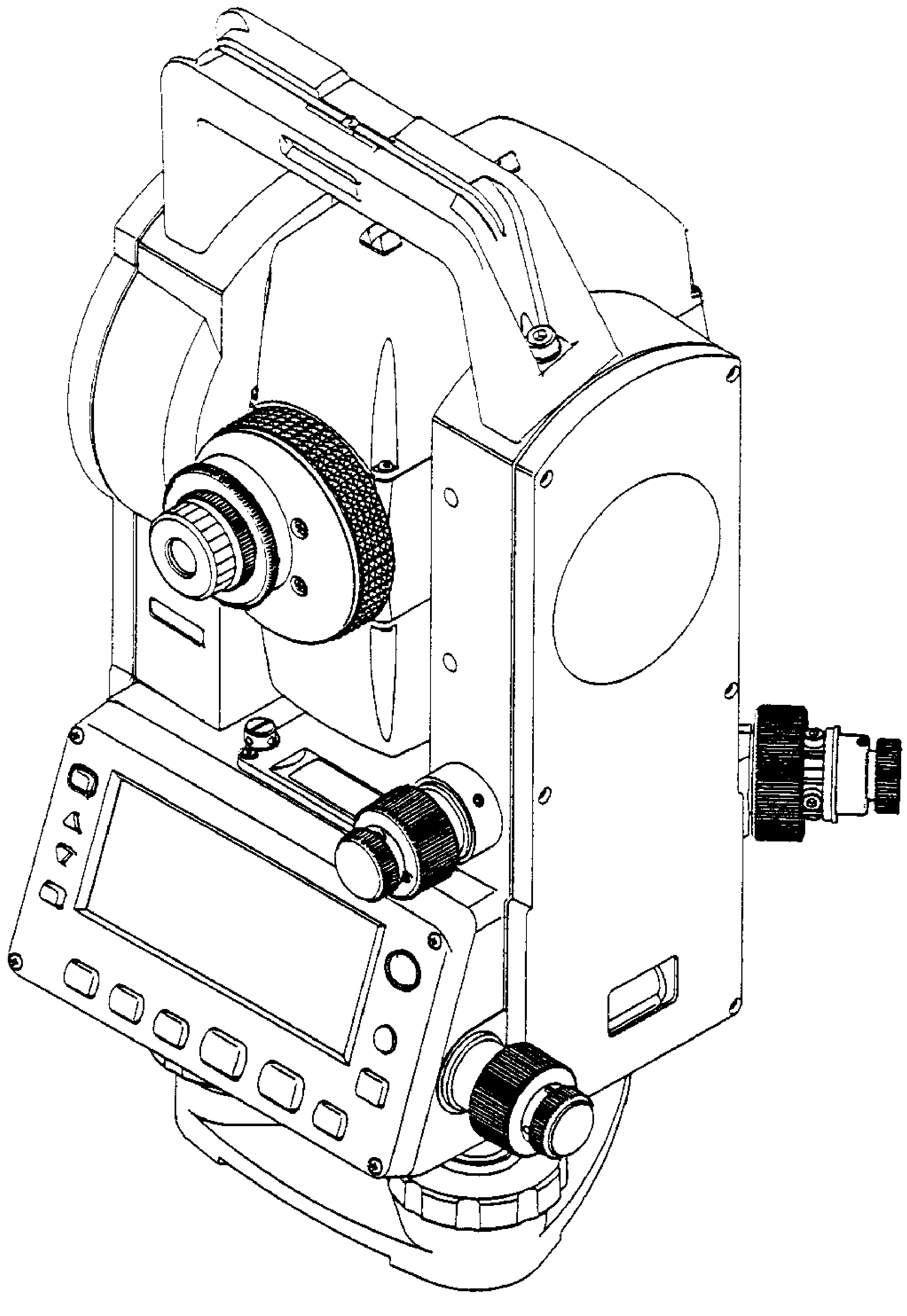
[57] **CLAIM**

The ornamental design of a measurement surveying device, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of the mesurement surveying device;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a top plan view thereof; and,
FIG. **7** is a bottom plan view thereof.

1 Claim, 7 Drawing Sheets



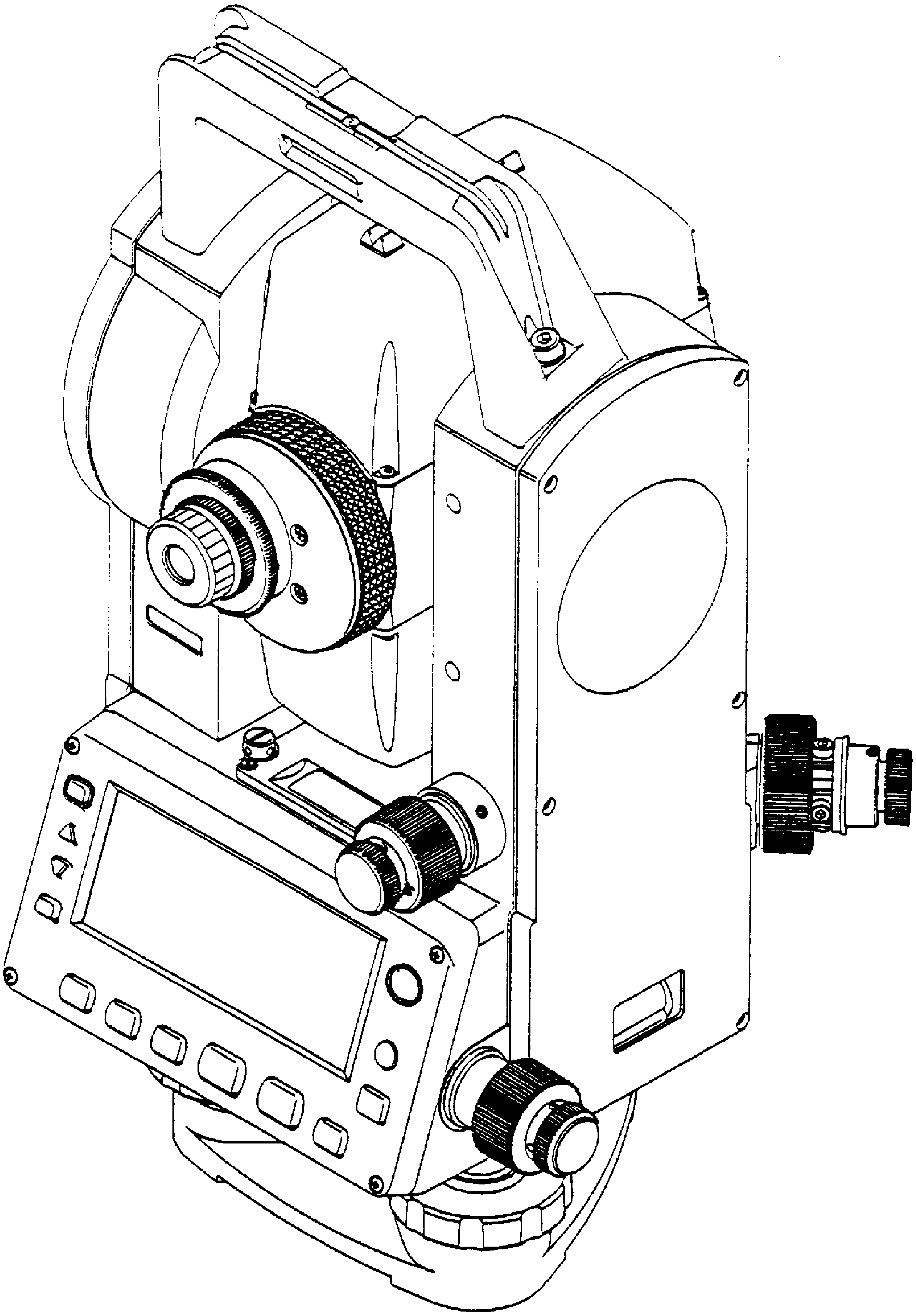


FIG. 1

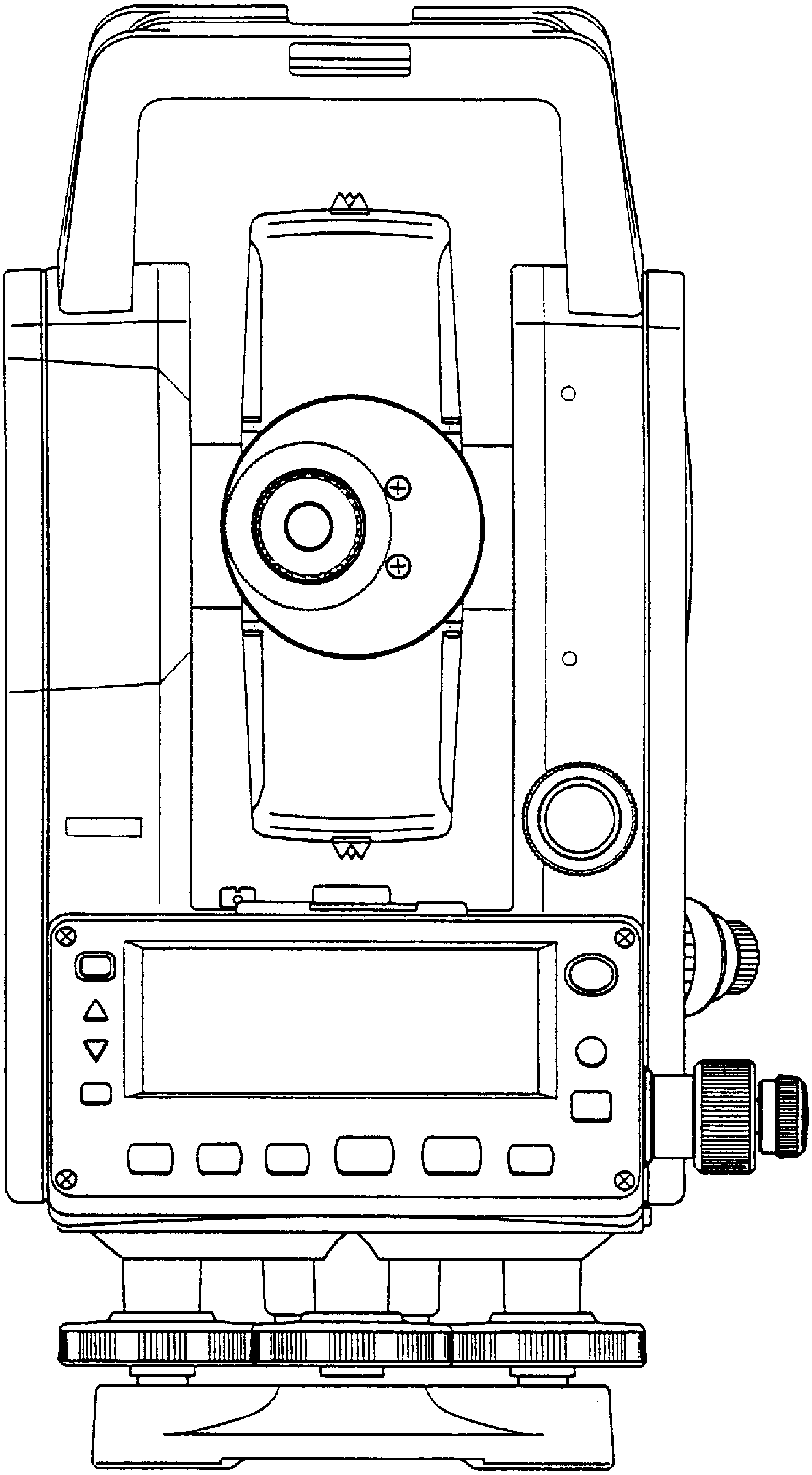
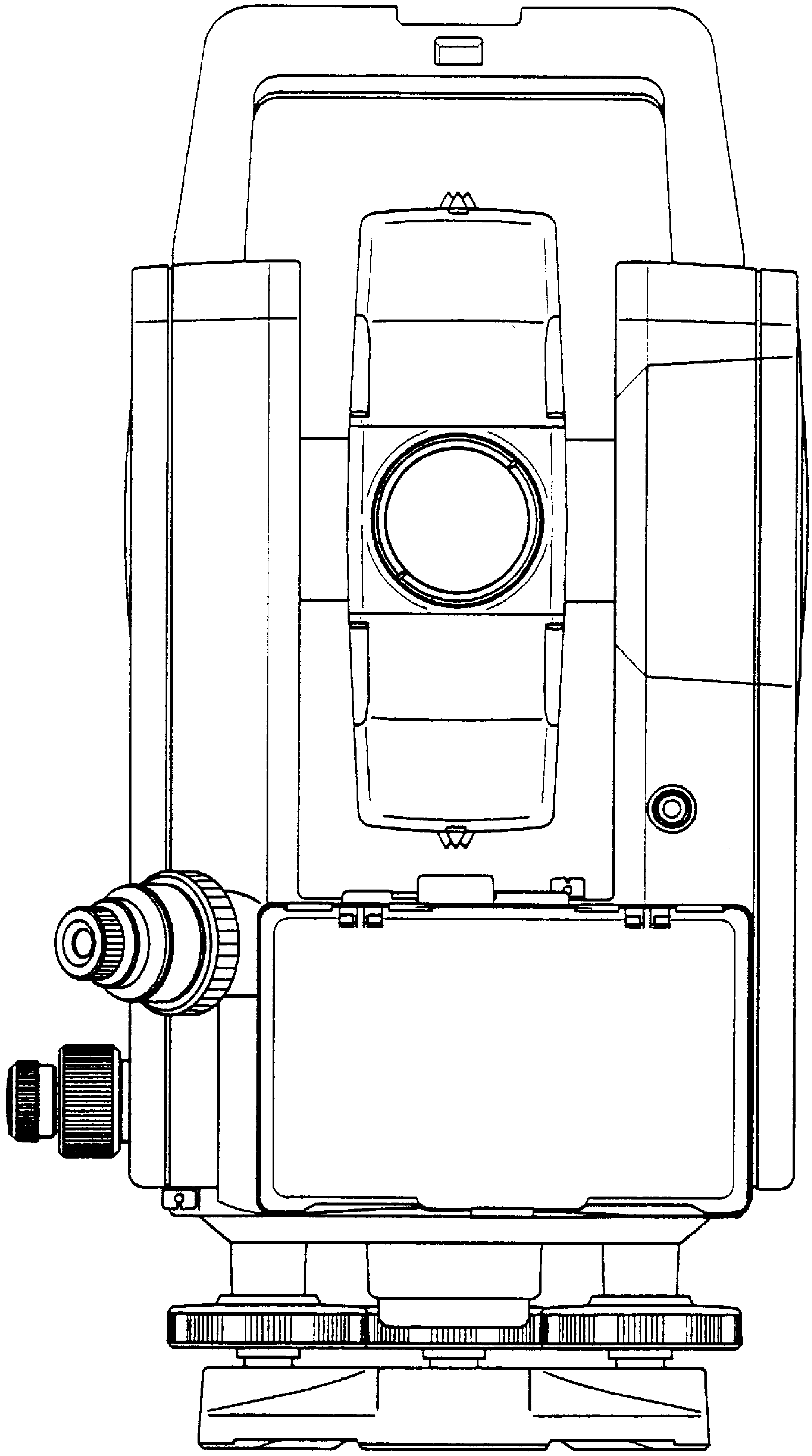


FIG. 2



F I G. 3

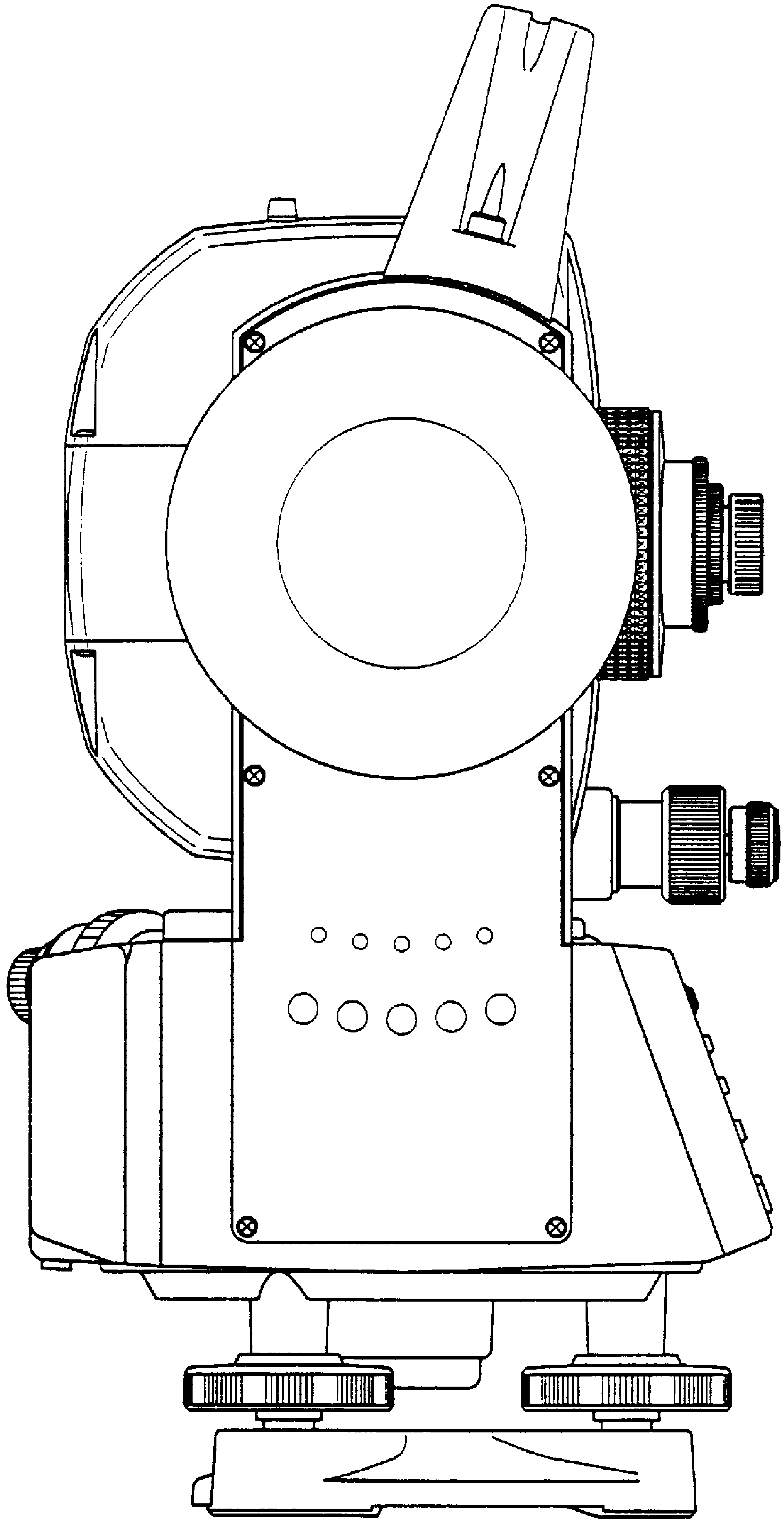


FIG. 4

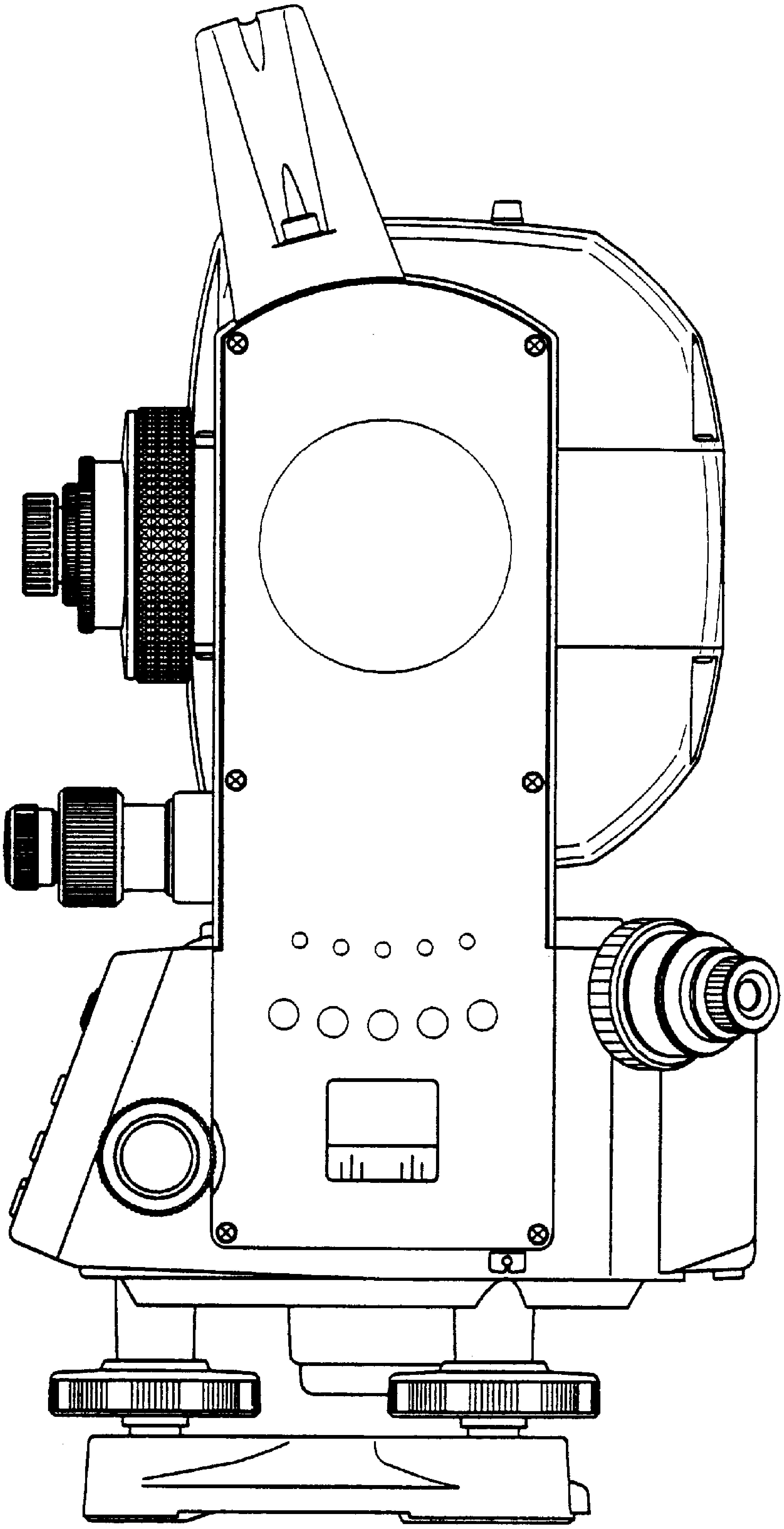
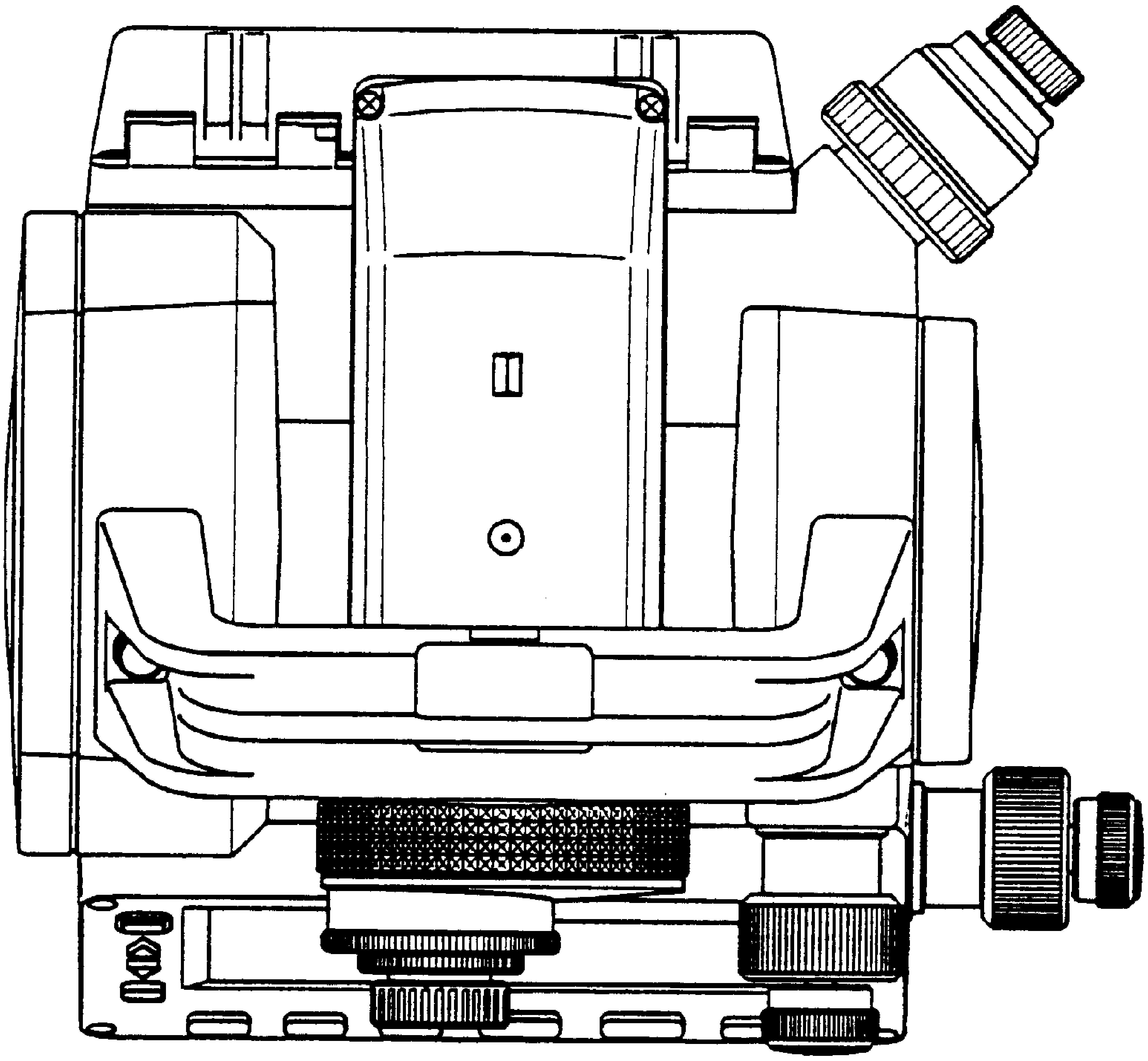


FIG. 5



F I G. 6

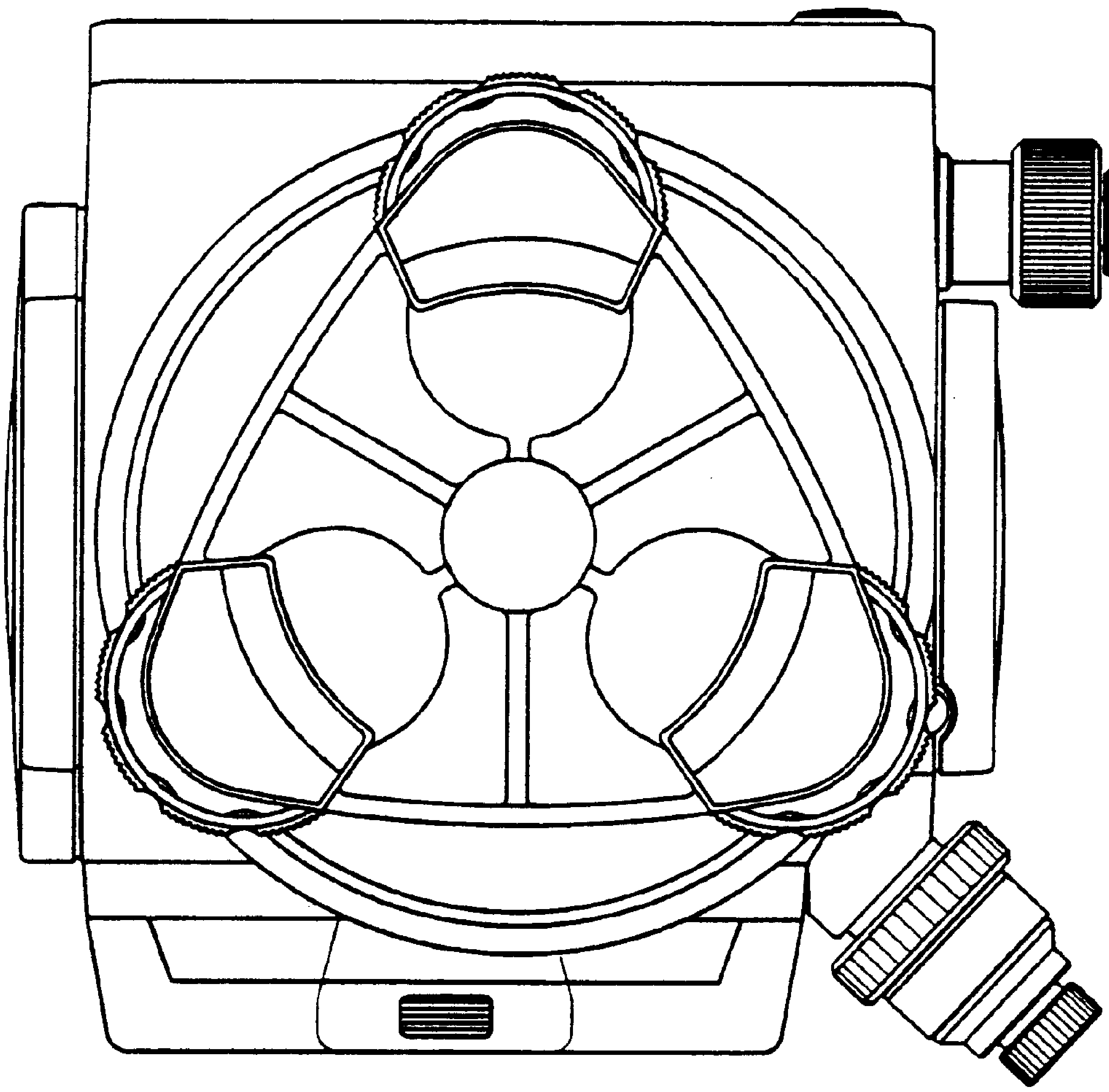


FIG. 7